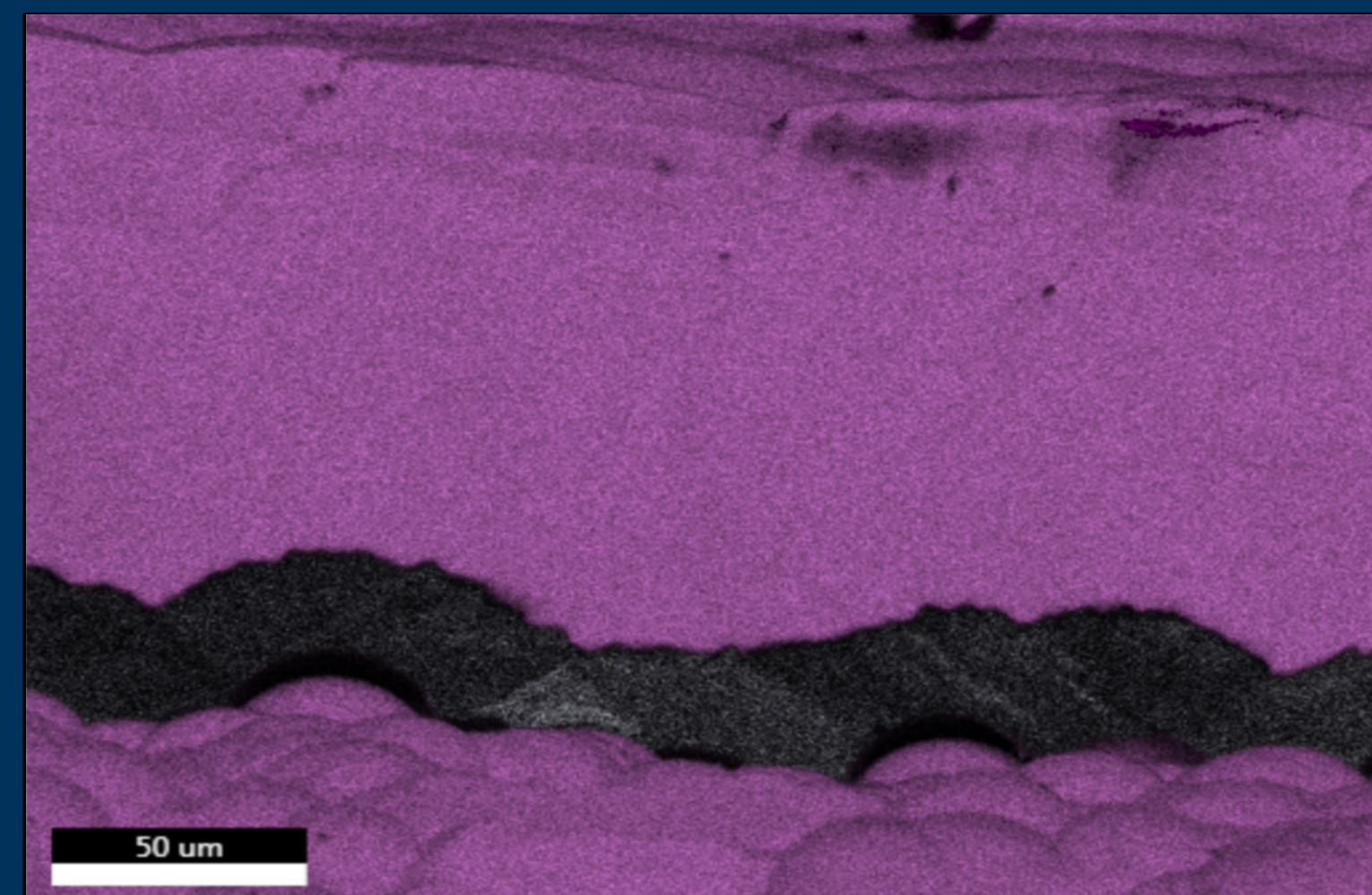


ETC Analytical Facilities

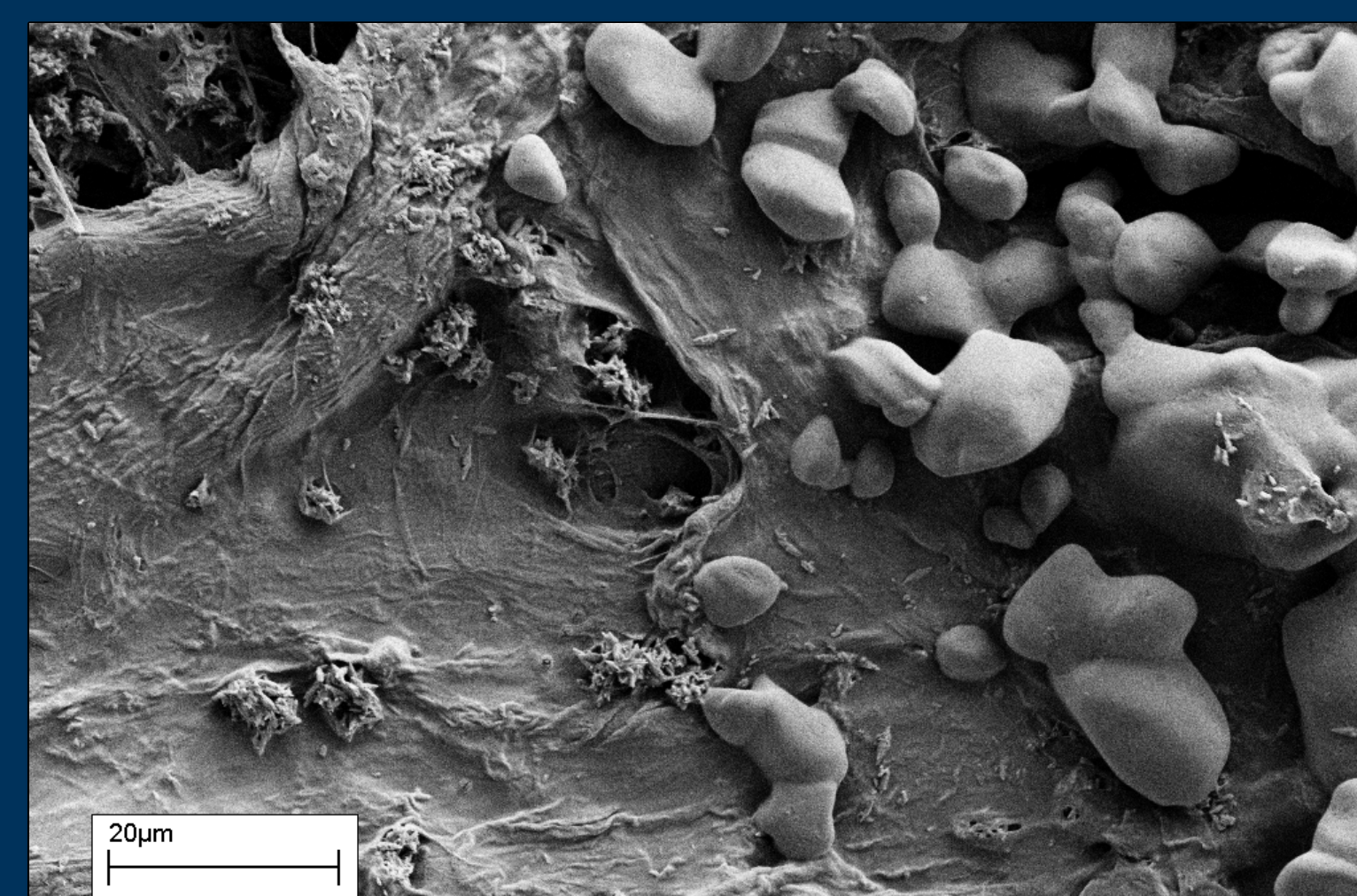
<http://www.brunel.ac.uk/etc>

- ❑ Scanning Electron Microscopy with EDXA*
- ❑ Field Emission Scanning Electron Microscopy with EDXA* and EBSD
- ❑ Transmission Electron Microscopy with ED, EDXA, GIF, EELS, in-situ CL
- ❑ Focussed Ion Beam Scanning Electron Microscopy with EDXA and EBSD
- ❑ X-ray Diffraction – powder,* capillary and single crystal
- ❑ Thermal Analysis – DSC, TGA, DMA
- ❑ Fourier Transform Infrared Spectroscopy* with imaging capability
- ❑ Raman spectroscopy
- ❑ UV/VIS/NIR Spectroscopy
- ❑ Atomic Force Microscopy
- ❑ Secondary Ion Mass Spectrometry
- ❑ Optical Microscopy
- ❑ Contact Angle Measurement
- ❑ Materials testing

* UKAS accredited techniques



SEM image of coated material, Anguilano, L.



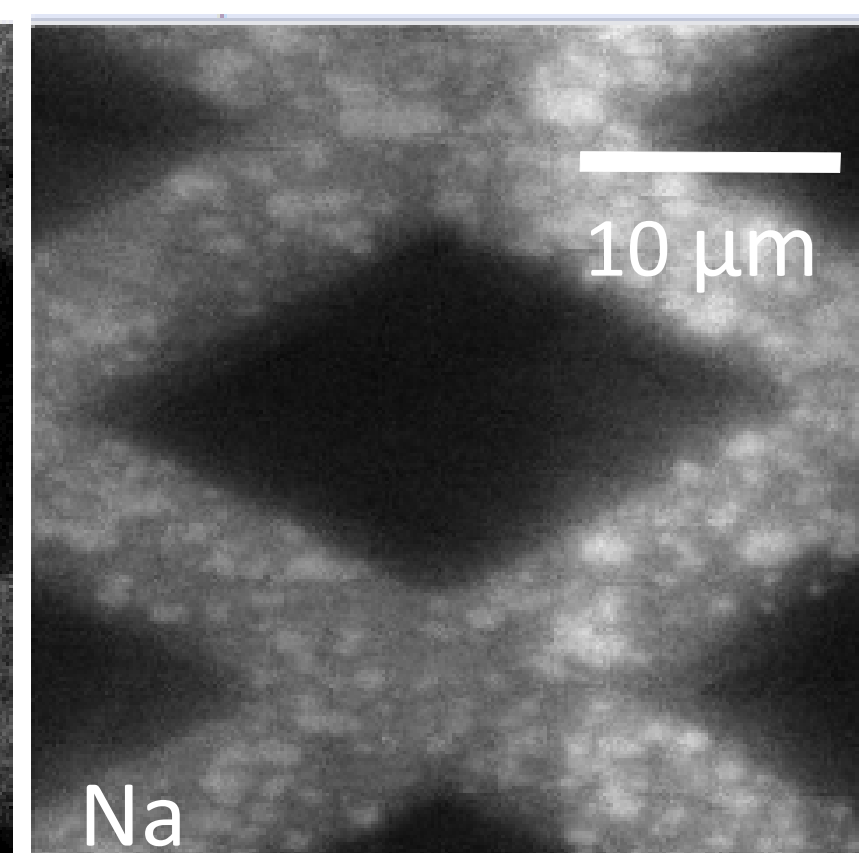
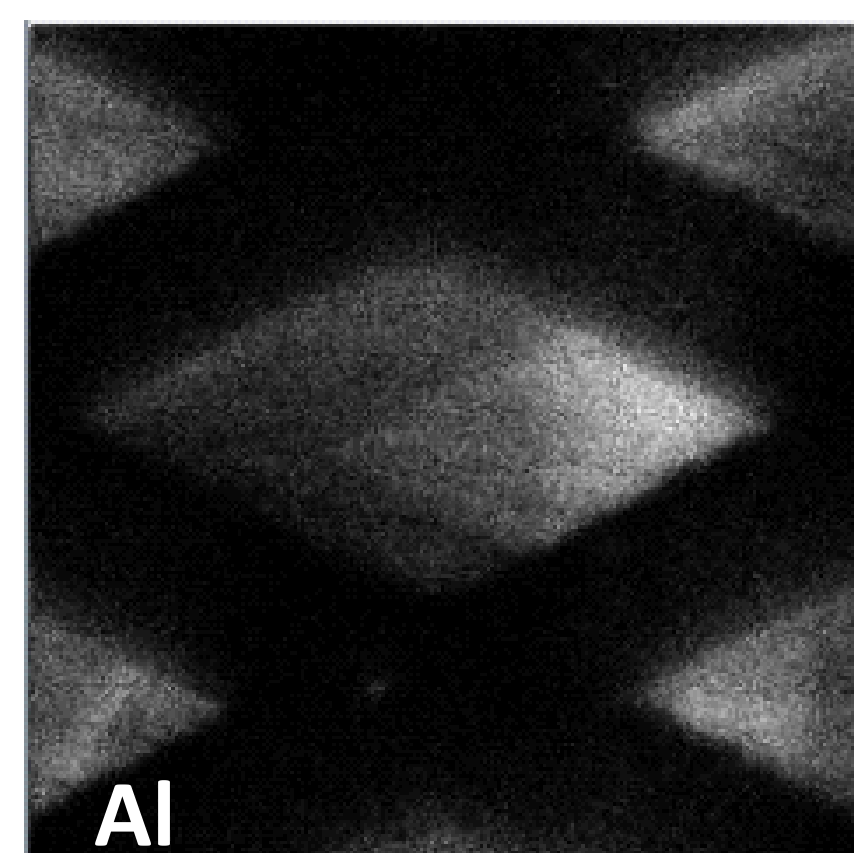
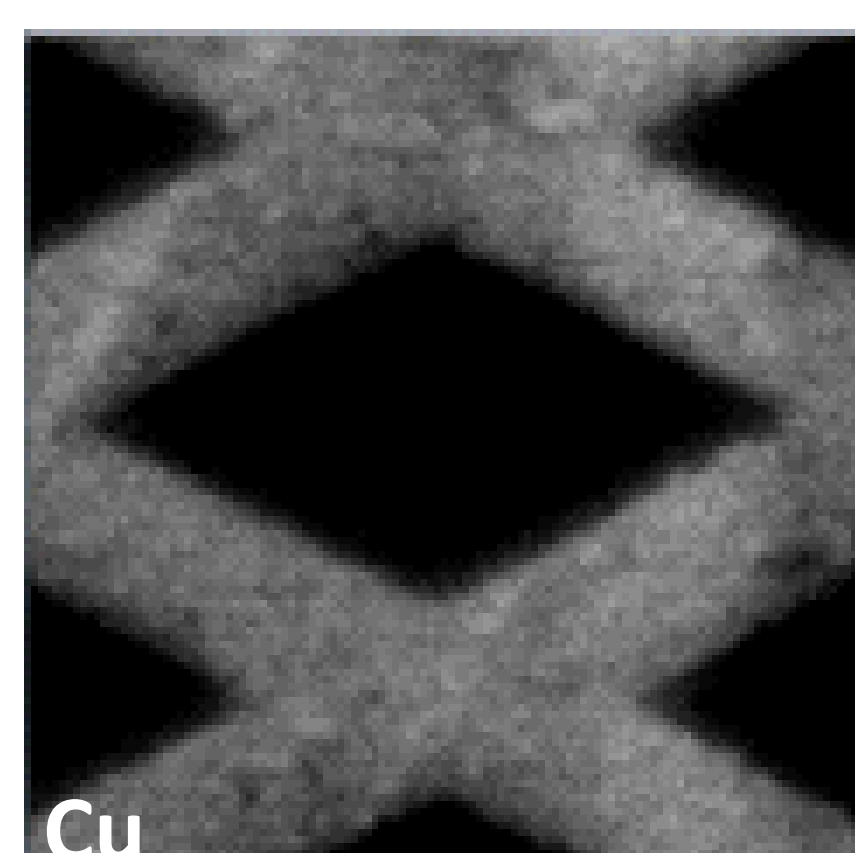
Ink on paper (SEM image). Attard Montalto, N.



Focused Ion Beam SEM, equipped with EDAX Octane Elite SDD EDX and EBSD



Transmission Electron Microscopy, equipped with X-ray, electron energy loss spectrometry and cathodoluminescence.



ToF SIMS ion maps of a copper grid on an aluminium surface, showing the chemical distribution. Ojeda, J.